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APPLICANT

Castrucci, Paul P.

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TECHNOLOGY CENTER 2800 U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
A.M.	AA	3,464,534	09/02/69	Muncheryan	197	181	
	AB	4,028,135	06/07/77	Vig et al.	134	1	
	AC	4,181,538	01/01/80	Narayan et al.	148	1.5	
	AD	4,292,093	09/29/81	Ownby et al.	357	59	
	AE	4,590,094	05/20/86	Ringer, Jr.	427	82	
	AF	4,680,616	07/14/87	Delahoy et al.	357	59	
	AG	4,867,796	09/19/89	Asmus et al.	131	1	
	AH	4,980,536	12/25/90	Asch et al.	219	121.68	
	AI	4,987,286	01/22/91	Allen	219	121.68	
	AJ	5,024,968	06/18/91	Engelsberg	437	173	
	AK	5,099,557	03/31/92	Engelsberg	29	25.01	

FOREIGN PATENT DOCUMENTS

		DOCUMENT	PUBLICATION DATE	COUNTRY	CLASS	SUB-CLASS	TRANS- LATION
	AL						
	AM						

OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)

A.M.	AN	Bedair et al., "Atomically Clean Surfaces by Pulsed Laser Bombardment" J. Applied Physics, Vol. 10, No. 12 (Nov. 1969)
	AO	Philip E. Ross, "Dust Busters: Laser Light Submicron Motes from Silicon Wafers" Scientific American 1980, vol. 262 No. 6, pp. 86 - 88
	AP	Author unknown, "Laser Activated Cleaning and Etching System and Method" IBM Technical Disclosure Bulletin December 1982, pp. 3775 - 3776
	AR	W. Zapka and A. Tam, "Particulate Removal from a Surface by Excimer Laser Radiation" CLEO 1990 Technical Digest, Series Vol. 7 pp. 226 -- 229 (1990)
	AS	K. Imen, S. J. Lee, and S. D. Allen, "Laser Assisted Micron Scale Particulate Removal" CLEO 1990 Technical Digest, Series Vol. 7 pp. 228 - 229 (1990)
	AT	K. Imen, S. J. Lee, and S. D. Allen "Laser-assisted micron scale particle removal" Applied Physics Letters Vol. 58 January 1991, p. 203 - 205

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
A-M	AA	5,151,135	09/29/92	Magee et al.	134	1	
	AB	5,283,417	02/01/94	Misawa et al.	219	121.85	
	AG	5,332,879	07/26/94	Radhakrishnan et al.	219	121.69	
	AD	5,366,559	11/22/94	Periasamy	134	1	
	AE	5,393,957	02/28/95	Misawa et al.	219	171.85	
	AF	5,466,908	11/14/95	Hosoya et al.	217	121.68	
	AG	5,482,561	01/09/96	Yeung et al.	134	1	
	AH	5,499,668	03/19/96	Katayama et al.	134	1	
	AI	5,531,857	07/02/96	Engelsberg et al.	156	345	
	AJ	5,592,879	01/14/97	Waizmann	101	416.1	
	AK	5,637,245	06/10/97	Shelton et al.	219	121.85	

FOREIGN PATENT DOCUMENTS

		DOCUMENT	PUBLI-CATION DATE	COUNTRY	CLASS	SUB-CLASS	TRANS- LATION
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/	AM						

OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)

A-M	AN	W. Zapka, W. Ziemlich, and A. C. Tam, "Efficient pulsed laser removal of 0.2 mm gold particles from a surface," Applied Physics Letters Vol. 58 No. 20, p. 2217- 2219 (May 1991)
	AO	Author unknown, "Elimination of Surface Debris in Laser Ablation of Polymers" IBM Technical Disclosure Bulletin, Vol 34, No. 4B, Sept. 1991, p. 233
	AP	Author unknown "Laser Cleaning of a Delicate (Easily Laser Damaged) Surface" IBM Technical Disclosure Bulletin, June 1992, pp. 70 - 71
	AR	Author unknown "Fast Laser Steam Cleaning by Continuous Film Deposition and Pulsed Laser Irradiation of a Moving Surface" IBM Technical Disclosure Bulletin, Vol. 39 No. 3 (March 1996) pp. 175 - 176
	AS	A. Engelsberg "Laser-Assisted Cleaning Proves Promising" Precision Cleaning, May 1995
	AT	R. Ariail "A Professional Method for Cleaning Optics" reprint of Journal of the Antique Telescope Society Spring/Summer 1995

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A.M	AA	5,643,472	07/01/97	Engelsberg et al.	216	65	
	AB	5,656,096	08/12/97	Van Alstyne	134	1	
	AC	5,669,979	09/23/97	Elliott et al.	134	1	
	AD	5,681,395	10/28/97	Werner	134	1	
	AE	5,751,897	05/12/98	Van Alstyne	392	419	
	AF	5,800,625	09/01/98	Engelsberg et al.	134	1	
	AG	5,814,156	09/29/98	Elliott et al.	134	1	
	AH	5,821,175	10/13/98	Engelsberg	438	795	
	AI	Re 35,981	12/08/98	Nagy et al.	219	121.68	
	AJ	5,958,268	09/28/99	Engelsberg et al.	219	121.84	
	AK						

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OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)

A.M	AN	D. J. Elliott et al., "Deep UV-Photoreactive Cleaning with Catadioptric Projection Optics and Reactive Gases" Future Fab International (date unknown)
	AO	B. Livshits et al., "Laser, dry and plasmaless, photoresist removal" Solid State Technology, July 1997, pp. 197 - 202
	AP	A. C. Tam et al., "Laser-cleaning techniques for removal of surface particulates" J. Applied Physics, Vol. 71 No. 7, pp. 3515 - 3523
	AR	
	AS	
	AT	

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